

**QoSinNoC: analysis of QoS-aware NoC architectures for mixed-criticality applications**

Avramenko, Serhiy; **Azad, Siavoosh Payandeh**; **Niazmand, Behrad**; **Raik, Jaan**; **Jenihhin, Maksim** 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 67-72 : ill <https://doi.org/10.1109/DDECS.2018.00-10>

**Replication-based deterministic testing of 2-dimensional arrays with highly interrelated cells**

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**Software-level TMR approach for on-board data processing in space applications**

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